

# A GENERALIZED INFINITE PRODUCT MEASURE

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**1. Introduction.** The standard definition of the product measure in a product of infinitely many measure spaces suffers from the defect that a product of measurable sets need not be measurable (see reference [2]). In this paper we define an extension of the standard product measure which is free of this defect. However, our extended product measure is not always a regular measure when the given measures are regular. Instead it is semi-regular; this means that measurable sets differ (in the sense of symmetric difference) from open sets by sets of arbitrarily small measure. In particular our theory applies to subsets of a Tychonoff cube of arbitrary cardinality.

**2. Definitions and notation.** By a *measure space* we mean a triple  $(S, \mathfrak{M}, m)$  consisting of a non-empty set  $S$ , a  $\sigma$ -field  $\mathfrak{M}$  of subsets of  $S$  and a countably additive measure  $m$  defined on  $\mathfrak{M}$ . Throughout this paper  $(X_\alpha, \mathfrak{M}_\alpha, \mu_\alpha)$  will denote a measure space for each  $\alpha$  contained in an infinite index set  $\Gamma$  and  $\mu_\alpha(X_\alpha) = 1$  for every  $\alpha \in \Gamma$ .

Let  $X = \prod_{\alpha \in \Gamma} X_\alpha$  denote the cartesian product of the collection  $\{X_\alpha : \alpha \in \Gamma\}$ . A subset  $A$  of  $X$  is called a measurable rectangle if it is of the form

$$(1) \quad A = \prod_{\alpha \in \Gamma} A_\alpha,$$

where  $A_\alpha \in \mathfrak{M}_\alpha$  and, with a finite number of exceptions,  $A_\alpha = X_\alpha$ . If  $\mu$  is a countably additive measure defined on a  $\sigma$ -field of subsets of  $X$  containing all measurable rectangles such that  $\mu(A) = \prod_{i=1}^n \mu_{\alpha_i}(A_{\alpha_i})$  for every measurable rectangle  $A = \prod_{\alpha \in \Gamma} A_\alpha$ , where  $\alpha_i$  are those indices for which  $A_{\alpha_i} \neq X_{\alpha_i}$ , then  $\mu$  is called an *infinite product measure*. Let  $\mathfrak{B}$  be the  $\sigma$ -field of subsets of  $X$  generated by the collection of all measurable rectangles. We shall let  $\mu$  denote the unique infinite product measure defined on  $\mathfrak{B}$  whose existence is established in [2].  $(X, \mathfrak{B}, \mu)$  will denote the completion of  $(X, \mathfrak{B}, \mu)$ .

Now let  $S$  be an arbitrary set. If  $A$  and  $B$  are subsets of  $S$ , the symmetric difference of  $A$  and  $B$  is denoted by  $A + B$ , i.e.,  $A + B = (A - B) \cup (B - A) = (A \cap B') \cup (A' \cap B)$ , where  $A'$  denotes the complement of  $A$  relative to  $S$ . A  $\sigma$ -ideal of subsets of  $S$  is a collection of subsets  $\mathfrak{D}$  of  $S$  such that  $A \in \mathfrak{D}$  and  $B \subseteq A$  imply  $B \in \mathfrak{D}$ , and  $A_i \in \mathfrak{D}$ ,  $i = 1, 2, \dots$ , imply  $\bigcup_{i=1}^{\infty} A_i \in \mathfrak{D}$ .

**3. An extension of  $\mu$ .** In the sequel we shall assume that  $\Gamma$  is uncountable. A subset  $A$  of  $X = \prod_{\alpha \in \Gamma} X_\alpha$  is said to *depend on a countable number of coordinates* if there exists a countable subset  $J$  of  $\Gamma$  such that a point  $(x_\alpha)_{\alpha \in \Gamma}$  of  $X$  belongs

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